

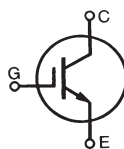
High Voltage IGBT

IXGH 32N120A3 IXGT 32N120A3

$$V_{CES} = 1200 \text{ V}$$

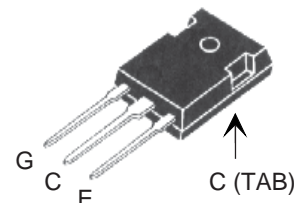
$$I_{C25} = 75 \text{ A}$$

$$V_{CE(sat)} \leq 2.35 \text{ V}$$

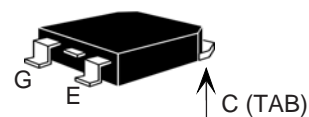


Symbol	Test Conditions	Maximum Ratings	
V_{CES}	$T_C = 25^\circ\text{C to } 150^\circ\text{C}$	1200	V
V_{CER}	$T_J = 25^\circ\text{C to } 150^\circ\text{C}, R_{GE} = 1 \text{ M}\Omega$	1200	V
V_{GES}	Continuous	± 20	V
V_{GEM}	Transient	± 30	V
I_{C25}	$T_C = 25^\circ\text{C}$, IGBT chip capability	75	A
I_{C110}	$T_C = 90^\circ\text{C}$	32	A
I_{CM}	$T_J \leq 150^\circ\text{C}$, $tp < 300 \mu\text{s}$	230	A
I_{AS}	$T_C = 25^\circ\text{C}$	20	A
E_{AS}	$T_C = 25^\circ\text{C}$	120	mJ
SSOA (RBSOA)	$V_{GE} = 15 \text{ V}$, $T_{VJ} = 150^\circ\text{C}$, $R_G = 20 \Omega$ Clamped inductive load, $V_{CE} < 0.8 V_{CES}$	$I_{CM} = 150$	A
P_C	$T_C = 25^\circ\text{C}$	300	W
T_J		-55 ... +150	$^\circ\text{C}$
T_{JM}		150	$^\circ\text{C}$
T_{stg}		-40 ... +125	$^\circ\text{C}$
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$
Plastic body		260	$^\circ\text{C}$
M_d	Mounting torque (TO-247)	1.3/10	Nm/lb.in.
Weight	TO-257	6	g
	TO-268	4	g

TO-247 (IXGH)



TO-268 (IXGT)



G = Gate C = Collector
E = Emitter TAB = Collector

Features

- International standard packages
- Low saturation voltage
- Avalanche rated
- MOS Gate turn-on
- drive simplicity
- Epoxy molding meets UL 94V-0

Applications

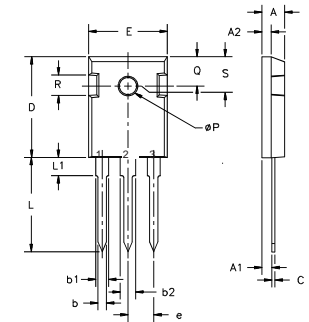
- Pulsed circuits
- Capacitor discharge

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$ unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{CES}	$I_C = 250 \mu\text{A}$, $V_{GE} = 0 \text{ V}$	1200		V
$V_{GE(th)}$	$I_C = 250 \mu\text{A}$, $V_{CE} = V_{GE}$	3.0		5.0 V
I_{CES}	$V_{CE} = V_{CES}$			50 μA
	$V_{GE} = 0 \text{ V}$		$T_J = 125^\circ\text{C}$	1 mA
I_{GES}	$V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$			$\pm 100 \text{ nA}$
$V_{CE(sat)}$	$I_C = I_{C110}$, $V_{GE} = 15 \text{ V}$, Note 1			2.35 V
	$I_C = 400 \text{ A}$, $V_{GE} = 30 \text{ V}$		11	V

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$ unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
g_{fs}	$I_C = 50\text{ A}$, $V_{CE} = 10\text{ V}$, Note 1	14	20	S
$I_{C(ON)}$	$V_{CE} = 10\text{ V}$, $V_{GE} = 15\text{ V}$, Note 1		15	A
C_{ies}			2150	pF
C_{oes}	$V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 1\text{ MHz}$		130	pF
C_{res}			48	pF
Q_g			89	nC
Q_{ge}	$I_C = 50\text{ A}$, $V_{GE} = 15\text{ V}$, $V_{CE} = 0.5 V_{CES}$		15	nC
Q_{gc}			34	nC
$t_{d(on)}$	Resistive load		39	ns
t_{ri}	$I_C = 100\text{ A}$, $V_{GE} = 20\text{ V}$, Note1		200	ns
$t_{d(off)}$	$V_{CE} = 960\text{ V}$, $R_G = 10\ \Omega$		140	ns
t_{fi}			1240	ns
R_{thJC}			0.42	K/W
R_{thCH}	(TO-247)		0.21	K/W

Note 1: Pulse test, $t \leq 300\text{ ms}$, duty cycle $\leq 2\%$

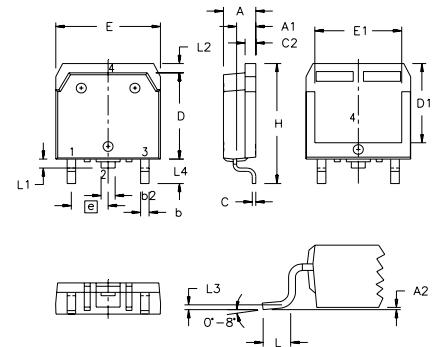
TO-247 AD Outline



Terminals: 1 - Gate
2 - Drain
3 - Source
Tab - Drain

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b ₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L ₁		4.50		.177
∅P	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	.242	BSC

TO-268 Outline



Terminals: 1 - Gate
2 - Drain
3 - Source
Tab - Drain

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.193	.201	4.90	5.10
A ₁	.106	.114	2.70	2.90
A ₂	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
b ₂	.075	.083	1.90	2.10
C	.016	.026	0.40	0.65
C ₂	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D ₁	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E ₁	.524	.535	13.30	13.60
e		.215 BSC		5.45 BSC
H	.736	.752	18.70	19.10
L	.094	.106	2.40	2.70
L ₁	.047	.055	1.20	1.40
L ₂	.039	.045	1.00	1.15
L ₃		.010 BSC		0.25 BSC
L ₄	.150	.161	3.80	4.10

PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from data gathered during objective characterizations of preliminary engineering lots; but also may yet contain some information supplied during a pre-production design evaluation. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

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Fig. 1. Output Characteristics @ 25°C

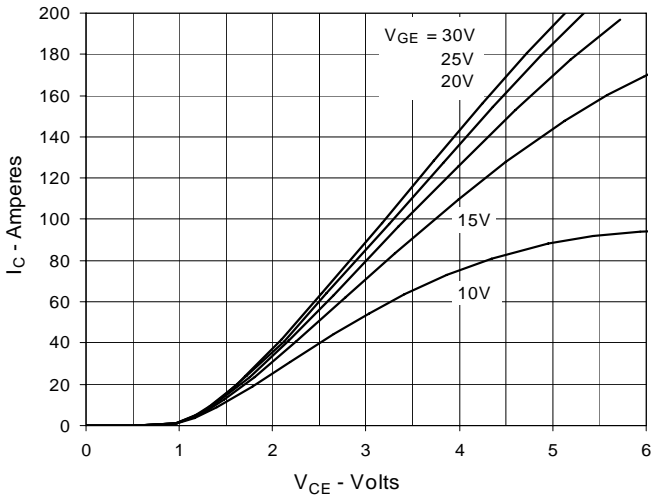


Fig. 2. Extended Output Characteristics @ 25°C

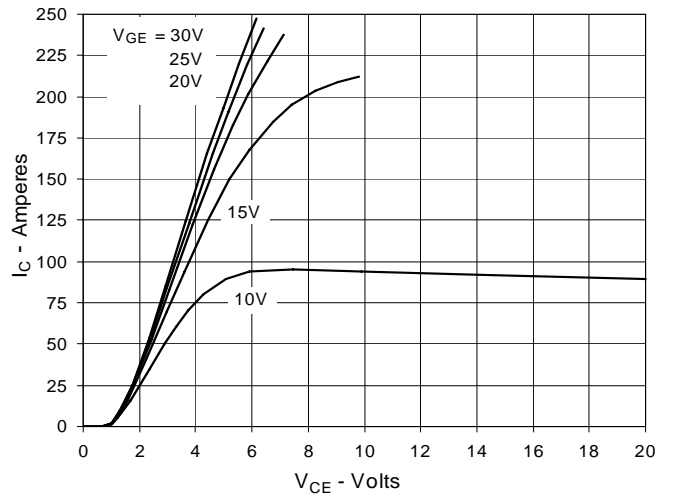


Fig. 3. Output Characteristics @ 125°C

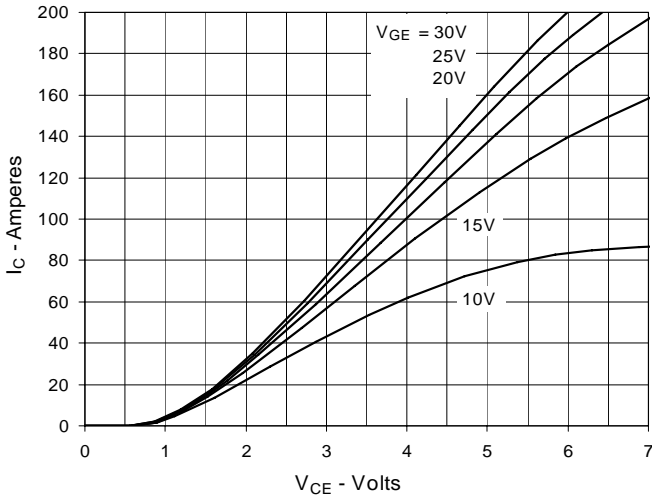


Fig. 4. Dependence of V_CE(sat) on Junction Temperature

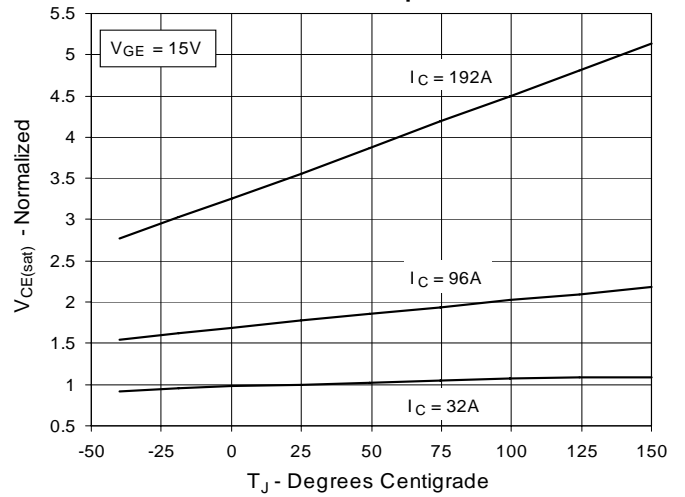


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

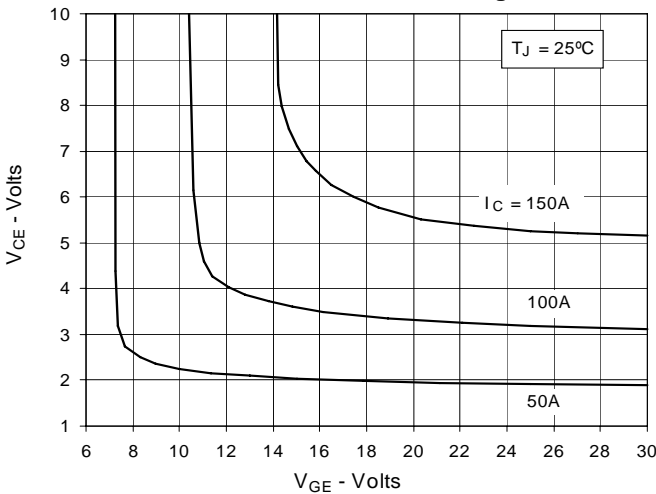


Fig. 6. Input Admittance

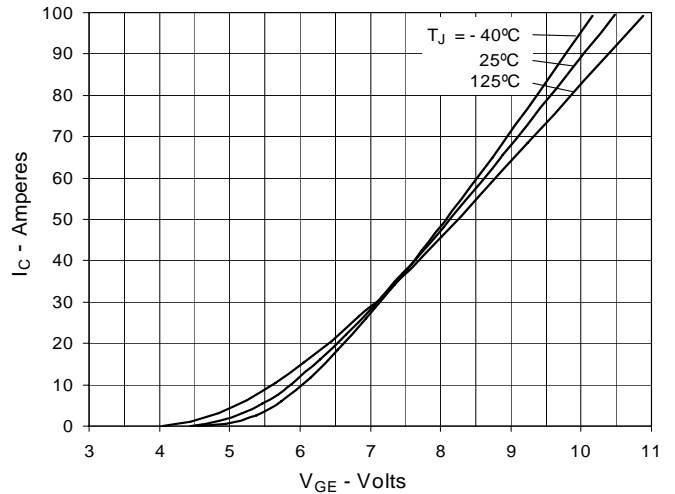


Fig. 7. Transconductance

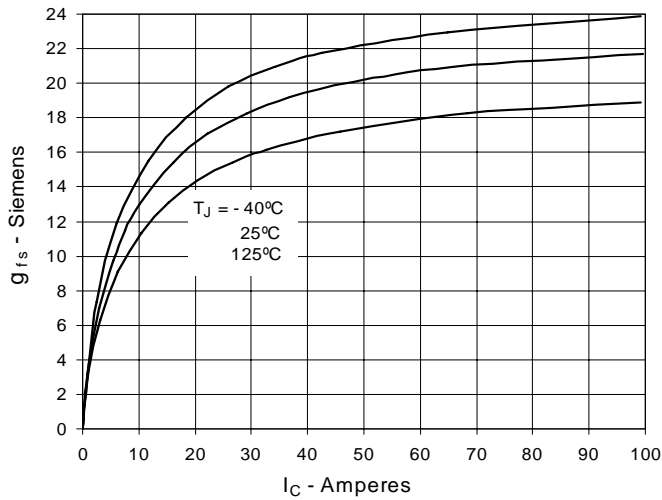


Fig. 8. Dependence of BV_{CES} & $V_{(th)GE}$ on Junction Temperature

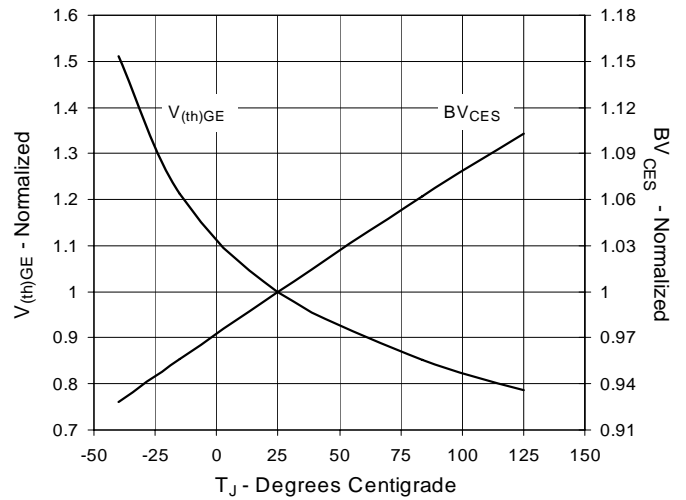


Fig. 9. Single-Pulsed Avalanche Energy vs. Junction Temperature

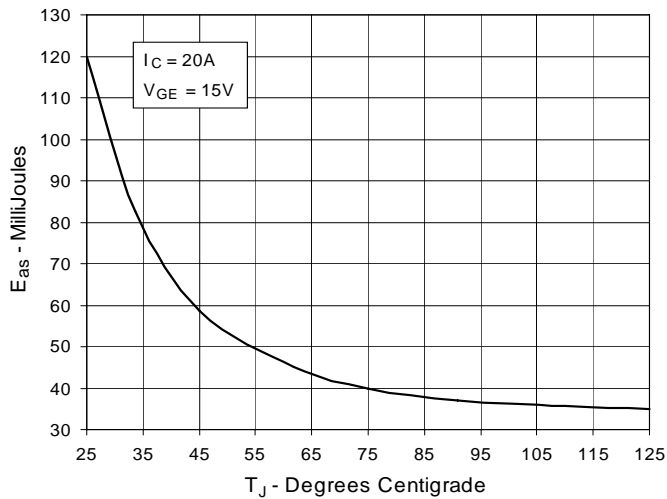


Fig. 10. Resistive Turn-on Rise Time vs. Gate Voltage

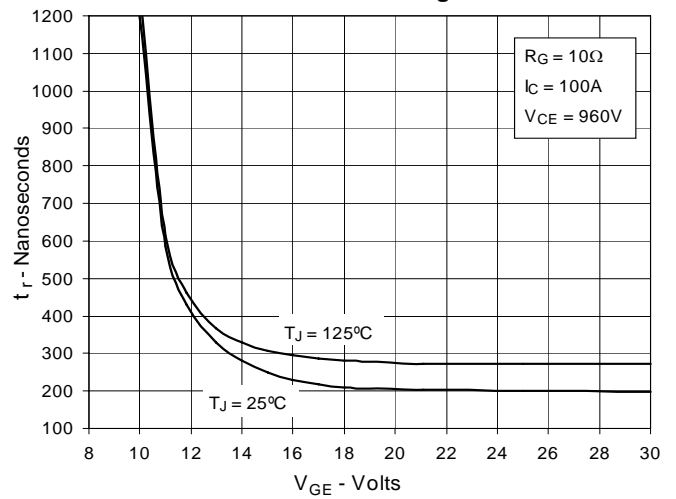


Fig. 11. Resistive Turn-on Rise Time vs. Junction Temperature

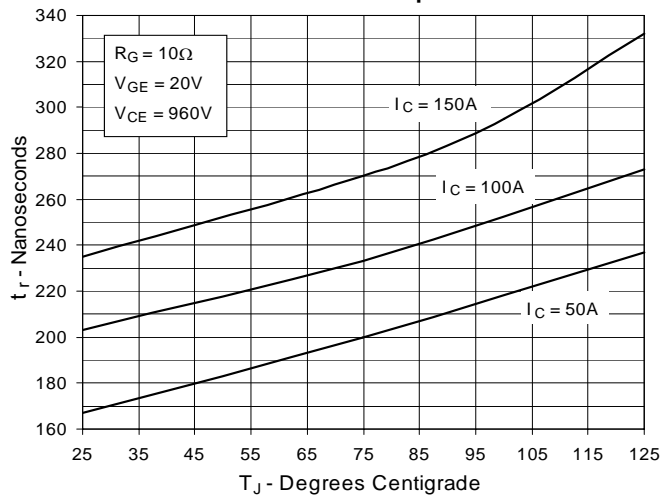
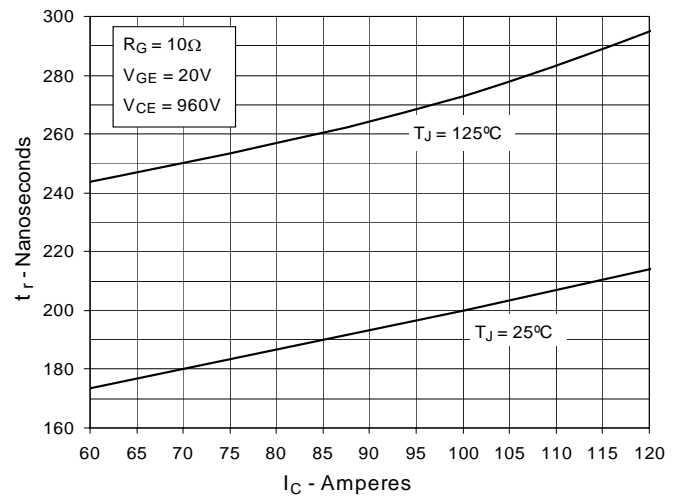


Fig. 12. Resistive Turn-on Rise Time vs. Collector Current



IXYS reserves the right to change limits, test conditions and dimensions.

Fig. 13. Resistive Turn-on Switching Times vs. Gate Resistance

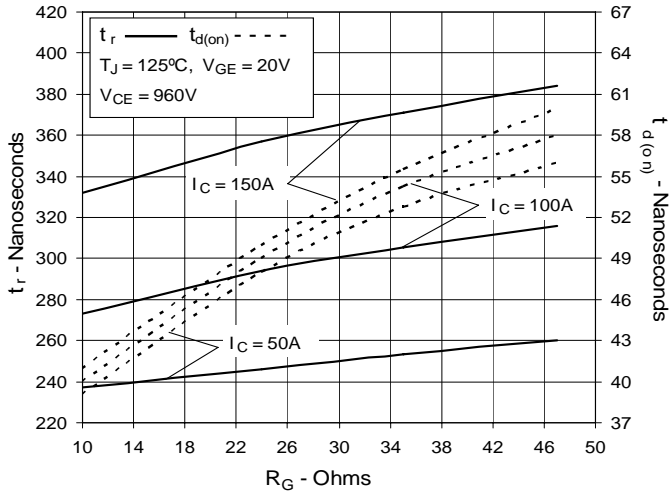


Fig. 14. Resistive Turn-off Switching Times vs. Junction Temperature

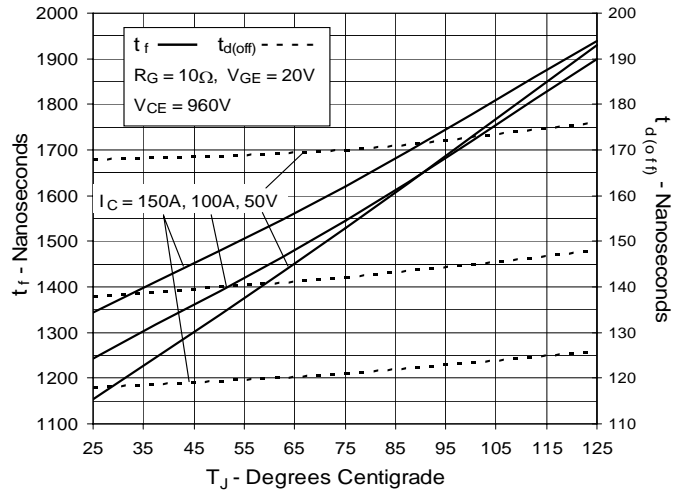


Fig. 15. Resistive Turn-off Switching Times vs. Collector Current

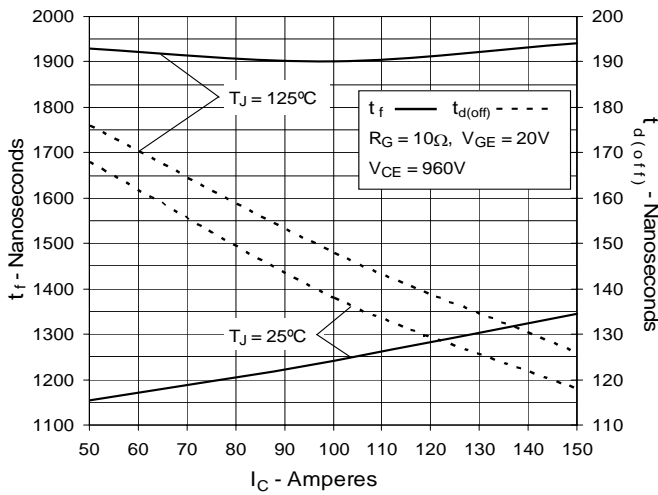


Fig. 16. Resistive Turn-off Switching Times vs. Gate Resistance

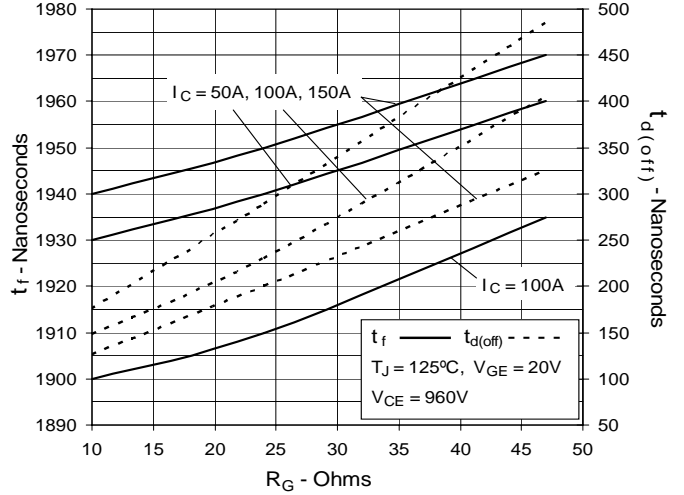


Fig. 17. Gate Charge

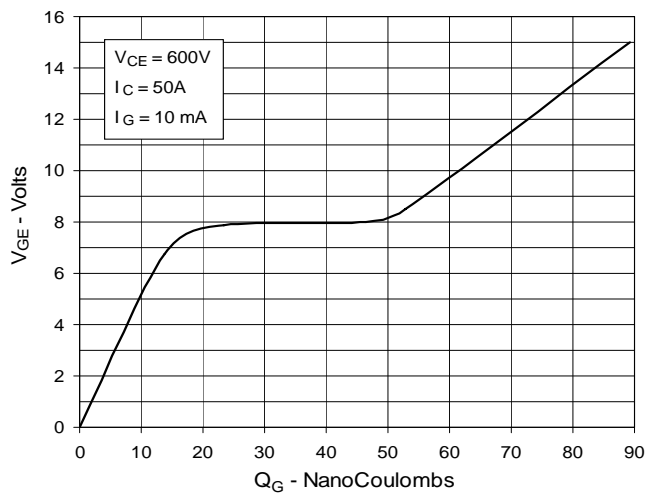


Fig. 18. Reverse-Bias Safe Operating Area

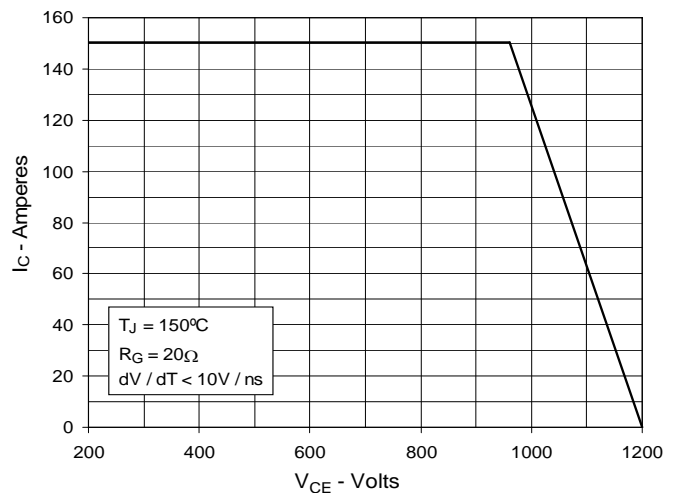


Fig. 19. Capacitance

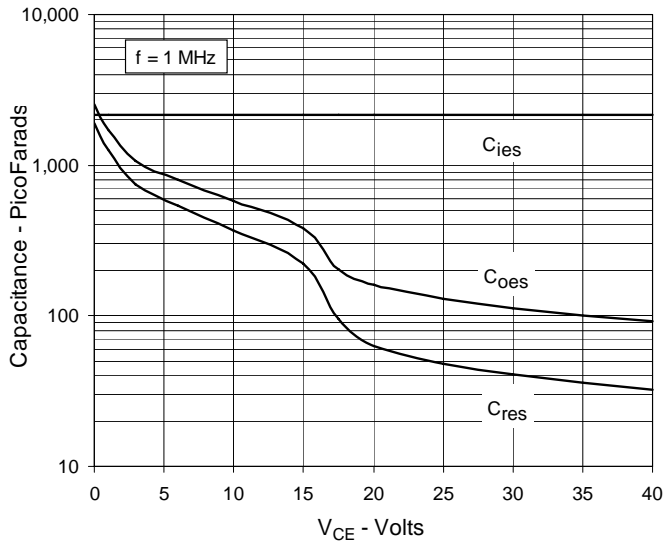


Fig. 20. Maximum Transient Thermal Resistance

